

February 1999 PRELIMINARY

FDP4020P/FDB4020P

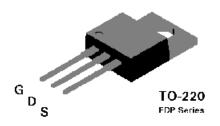
P-Channel 2.5V Specified Enhancement Mode Field Effect Transistor

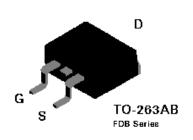
General Description

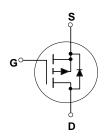
This P-Channel low threshold MOSFET has been designed for use as a linear pass element for low voltage outputs. In addition, the part may be used as a low voltage load switch when switching outputs on or off for power management. The part may also be used in conjunction with DC-DC converters requiring P-Channel.

Features

- 16 A, -20 V. $R_{DS(on)}$ = 0.08 Ω @ V_{GS} = -4.5 V $R_{DS(on)}$ = 0.11 Ω @ V_{GS} = -2.5 V.
- Critical DC electrical parameters specified at elevated temperature.
- High density cell design for extremely low $R_{\rm DS(on)}$
- TO-220 and TO-263 (D²PAK) package for both through hole and surface mount applications.
- 175°C maximum junction temperature rating.







Absolute Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter	FDP4020P	FDB4020P	Units
V _{DSS}	Drain-Source Voltage	-2	0	V
V _{GSS}	Gate-Source Voltage	±	8	V
I _D	Drain Current - Continuous	-1	6	А
	- Pulsed	-4	8	
P _D	Total Power Dissipation @ T _C = 25°C	37.5		W
	Derate above 25∘C	0.:	25	W/°C
T_J , T_{STG}	Operating and Storage Junction Temperature Range	-65 to +175		°C
Thormal Characteristics				

<u>Thermal Characteristics</u>

$R_{\theta^{JC}}$	Thermal Resistance, Junction-to- Case	4	°C/W		
$R_{\theta^{JA}}$	Thermal Resistance, Junction-to- Ambient	(Note 1)	62.5	40	°C/W

Package Outlines and Ordering Information

Device Marking	Device	Reel Size	Tape Width	Quantity
FDP4020P	FDP4020P	13"	12mm	2500 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	V_{GS} = 0 V, I_D = -250 μA	-20			V
ABVDSS ∆TJ	Breakdown Voltage Temperature Coefficient	I _D = -250 μA, Referenced to 25°C		-28		mV/∘C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -16 V, V _{GS} = 0 V			-1	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 8 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA
I_{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -8 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-0.4	-0.58	-1	V
ΔVGS(th) ΔT,J	Gate Threshold Voltage Temperature Coefficient	I_D = -250 μ A, Referenced to 25°C		2		mV/°C
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = -4.5 \text{ V}, I_D = -8 \text{ A},$ $V_{GS} = -4.5 \text{ V}, I_D = -8 \text{ A}, T_J = 125^{\circ}\text{C}$ $V_{GS} = -2.5 \text{ V}, I_D = -7 \text{ A}$		0.068 0.098 0.096	0.08 0.13 0.110	Ω
I _{D(on)}	On-State Drain Current	V _{GS} = -4.5 V, V _{DS} = -5 V	-20			Α
g FS	Forward Transconductance	V _{DS} = -5 V, I _D = -8 A		14		S
Dynamic	Characteristics					
C _{iss}	Input Capacitance	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V},$		665		pF
Coss	Output Capacitance	f = 1.0 MHz		270		pF
C _{rss}	Reverse Transfer Capacitance			70		pF
Switchin	q Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = -5 \text{ V}, I_D = -1 \text{ A},$		8	16	ns
t _r	Turn-On Rise Time	$V_{GS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$		24	38	ns
t _{d(off)}	Turn-Off Delay Time			50	80	ns
t _f	Turn-Off Fall Time			29	45	ns
Q _g	Total Gate Charge	$V_{DS} = -5 V$,		9.5	13	nC
Q _{gs}	Gate-Source Charge	$I_D = -16 \text{ A}, V_{GS} = -4.5 \text{ V}$		1.3		nC
Q_{gd}	Gate-Drain Charge			2.2		nC
Drain-So	urce Diode Characteristics	s and Maximum Ratings				
Is	Maximum Continuous Drain-Sour	ce Diode Forward Current (Note 2)			-16	Α
I _{SM}	Maximum Pulsed Drain-Source D	iode Forward Current (Note 2)			-48	
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -16 \text{ A}$ (Note 2)			-1.2	V

Notes:

R_{θ,JA} is the sum of the juntion-to-case and case-to-ambient thermal resistance. For T0-263 the device is mounted on circuit board with a 1in² pad of 2 oz. copper.
 Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2.0%

Typical Characteristics

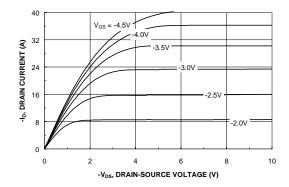


Figure 1. On-Region Characteristics.

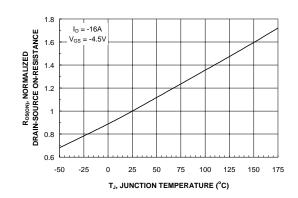


Figure 3. On-Resistance Variation with Temperature.

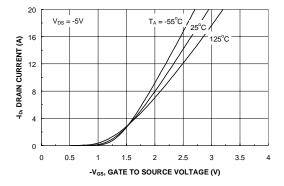


Figure 5. Transfer Characteristics.

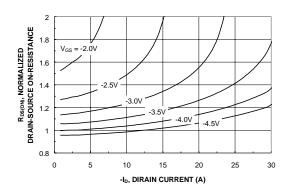


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

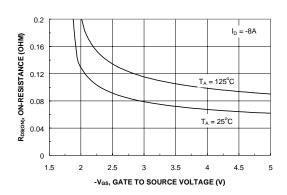


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

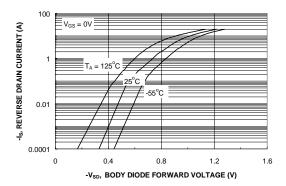
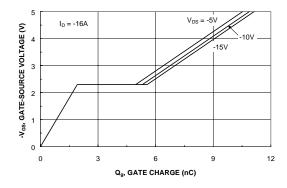


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics (continued)



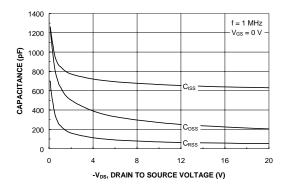


Figure 7. Gate-Charge Characteristics.

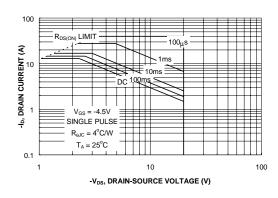


Figure 8. Capacitance Characteristics.

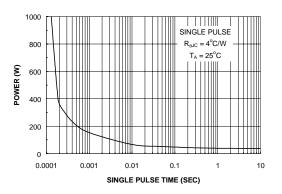


Figure 9. Maximum Safe Operating Area.



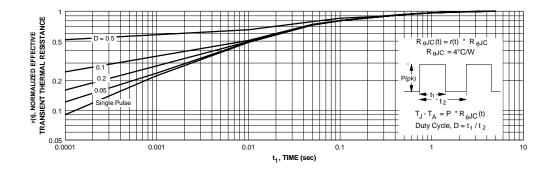
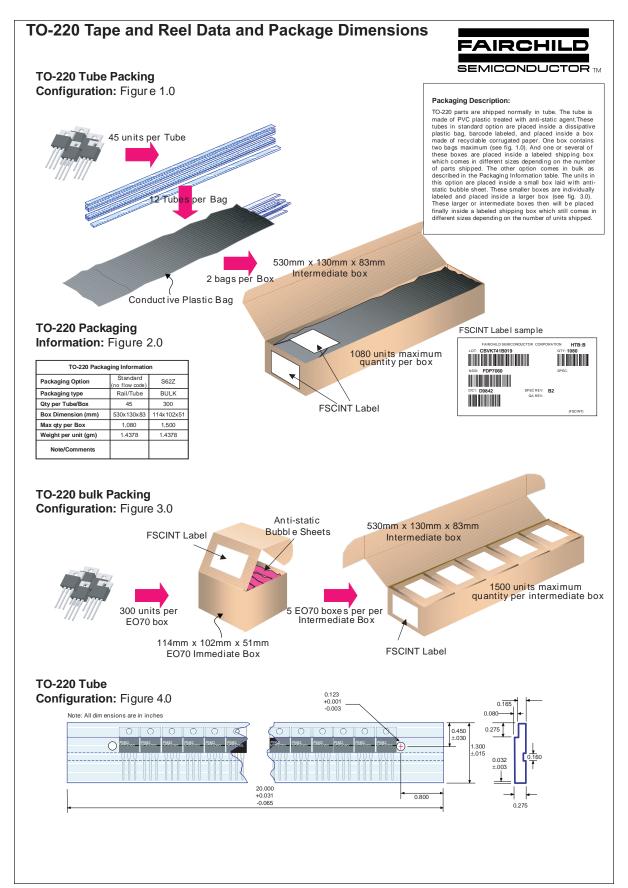


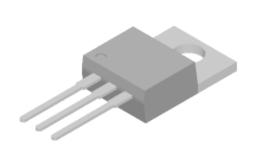
Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1. Transient themal response will change depending on the circuit board design.

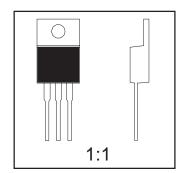


TO-220 Tape and Reel Data and Package Dimensions, continued

TO-220 (FS PKG Code 37)

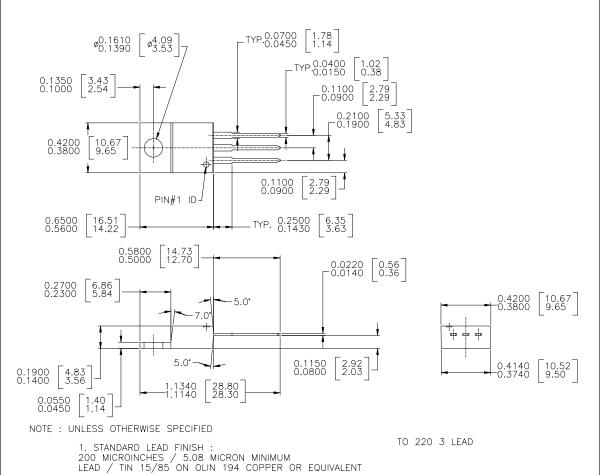


2. DIMENSION BASED ON JEDEC STANDARD TO-220 VARIATION AB, ISSUE J, DATED 3/24/87



Scale 1:1 on letter size paper
Dimensions shown below are in:
inches [millimeters]

Part Weight per unit (gram): 1.4378



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